

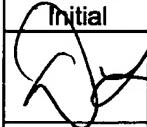
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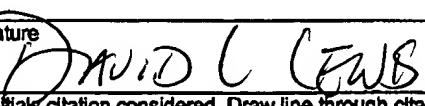
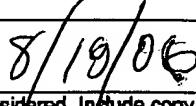
Sheet 1 of 1

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| Substitute Form PTO-1449 (Modified) | | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 07977-008004 | Application No. 09/504,235 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b)) | | Applicant Shunpei Yamazaki et al. | | |
| | | Filing Date February 15, 2000 | Group Art Unit 2673 | |

| U.S. Patent Documents | | | | | | | |
|------------------------------|-----------|-----------------|------------------|----------|-------|----------|----------------------------|
| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
| | AA | | | | | | |
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| Foreign Patent Documents or Published Foreign Patent Applications | | | | | | | |
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| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Sub-class | Translation |
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|  | AL | JP06-504139 | 12 MAY 1994 | JAPAN | — | — | Abtract |
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| Other Documents (include Author, Title, Date, and Place of Publication) | | |
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| Examiner Initial | Desig. ID | Document |
|  | AQ | Sumiyoshi et al., "DEVICE LAYER TRANSFERRED POLY-Si TFT ARRAY FOR HIGH RESOLUTION LIQUID CRYSTAL PROJECTOR", International Electron Devices Meeting, December 3-6, 1989, IEDM 89, pp. 165-168. |
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| Examiner Signature |  | Date Considered |  |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | |